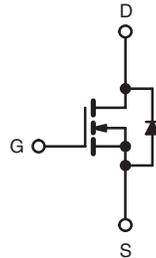
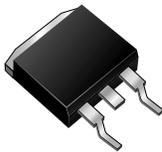


Power MOSFET

PRODUCT SUMMARY

| | | |
|---------------------------|------------------------|------|
| V_{DS} (V) | 250 | |
| $R_{DS(on)}$ (Ω) | $V_{GS} = 10\text{ V}$ | 0.28 |
| Q_g (Max.) (nC) | 68 | |
| Q_{gs} (nC) | 11 | |
| Q_{gd} (nC) | 35 | |
| Configuration | Single | |

SMD-220


N-Channel MOSFET

FEATURES

- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available


 Available
RoHS*
 COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SMD-220 is a surface mount power package capable of accommodating die size up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The SMD-220 is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application.

ORDERING INFORMATION

| | | | |
|----------------|-------------|----------------------------|----------------------------|
| Package | SMD-220 | SMD-220 | SMD-220 |
| Lead (Pb)-free | IRF644SPbF | IRF644STRLPbF ^a | IRF644STRRPbF ^a |
| | SiHF644S-E3 | SiHF644STL-E3 ^a | SiHF644STR-E3 ^a |
| SnPb | IRF644S | IRF644STRL ^a | IRF644STRR ^a |
| | SiHF644S | SiHF644STL ^a | SiHF644STR ^a |

Note

a. See device orientation.

ABSOLUTE MAXIMUM RATINGS $T_C = 25\text{ }^\circ\text{C}$, unless otherwise noted

| PARAMETER | SYMBOL | LIMIT | UNIT |
|---|----------|-----------------------------------|---------------------|
| Drain-Source Voltage | V_{DS} | 250 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | |
| Continuous Drain Current | I_D | $T_C = 25\text{ }^\circ\text{C}$ | A |
| | | $T_C = 100\text{ }^\circ\text{C}$ | |
| Pulsed Drain Current ^a | I_{DM} | 56 | W/ $^\circ\text{C}$ |
| Linear Derating Factor | | 1.0 | |
| Linear Derating Factor (PCB Mount) ^e | | 0.025 | |
| Single Pulse Avalanche Energy ^b | E_{AS} | 550 | mJ |
| Avalanche Current ^a | I_{AR} | 14 | A |
| Repetitive Avalanche Energy ^a | E_{AR} | 13 | mJ |
| Maximum Power Dissipation | P_D | $T_C = 25\text{ }^\circ\text{C}$ | W |
| | | $T_A = 25\text{ }^\circ\text{C}$ | |

* Pb containing terminations are not RoHS compliant, exemptions may apply

| ABSOLUTE MAXIMUM RATINGS $T_C = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | |
|---|----------------|------------------|------------------|
| PARAMETER | SYMBOL | LIMIT | UNIT |
| Peak Diode Recovery dV/dt^c | dV/dt | 4.8 | V/ns |
| Operating Junction and Storage Temperature Range | T_J, T_{stg} | - 55 to + 150 | $^\circ\text{C}$ |
| Soldering Recommendations (Peak Temperature) | for 10 s | 300 ^d | |

Notes

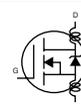
- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50\text{ V}$, starting $T_J = 25\text{ }^\circ\text{C}$, $L = 4.5\text{ mH}$, $R_G = 25\text{ }\Omega$, $I_{AS} = 14\text{ A}$ (see fig. 12).
- c. $I_{SD} \leq 14\text{ A}$, $dI/dt \leq 150\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DS}$, $T_J \leq 150\text{ }^\circ\text{C}$.
- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).

| THERMAL RESISTANCE RATINGS | | | | |
|--|------------|------|------|---------------------------|
| PARAMETER | SYMBOL | TYP. | MAX. | UNIT |
| Maximum Junction-to-Ambient | R_{thJA} | - | 62 | $^\circ\text{C}/\text{W}$ |
| Maximum Junction-to-Ambient (PCB Mount) ^a | R_{thJA} | - | 40 | |
| Maximum Junction-to-Case (Drain) | R_{thJC} | - | 1.0 | |

Note

- a. When mounted on 1" square PCB (FR-4 or G-10 material).

| SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | | | |
|---|---------------------|--|------|------|-----------|---------------------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| Static | | | | | | |
| Drain-Source Breakdown Voltage | V_{DS} | $V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$ | 250 | - | - | V |
| V_{DS} Temperature Coefficient | $\Delta V_{DS}/T_J$ | Reference to $25\text{ }^\circ\text{C}$, $I_D = 1\text{ mA}$ | - | 0.34 | - | $\text{V}/^\circ\text{C}$ |
| Gate-Source Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 2.0 | - | 4.0 | V |
| Gate-Source Leakage | I_{GSS} | $V_{GS} = \pm 20\text{ V}$ | - | - | ± 100 | nA |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 250\text{ V}$, $V_{GS} = 0\text{ V}$ | - | - | 25 | μA |
| | | $V_{DS} = 200\text{ V}$, $V_{GS} = 0\text{ V}$, $T_J = 125\text{ }^\circ\text{C}$ | - | - | 250 | |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS} = 10\text{ V}$, $I_D = 8.4\text{ A}^b$ | - | - | 0.28 | Ω |
| Forward Transconductance | g_{fs} | $V_{DS} = 50\text{ V}$, $I_D = 8.4\text{ A}^b$ | 6.7 | - | - | S |
| Dynamic | | | | | | |
| Input Capacitance | C_{iss} | $V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1.0\text{ MHz}$, see fig. 5 | - | 1300 | - | pF |
| Output Capacitance | C_{oss} | | - | 330 | - | |
| Reverse Transfer Capacitance | C_{rss} | | - | 85 | - | |
| Total Gate Charge | Q_g | $V_{GS} = 10\text{ V}$, $I_D = 7.9\text{ A}$, $V_{DS} = 200\text{ V}$, see fig. 6 and 13 ^b | - | - | 68 | nC |
| Gate-Source Charge | Q_{gs} | | - | - | 11 | |
| Gate-Drain Charge | Q_{gd} | | - | - | 35 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = 125\text{ V}$, $I_D = 7.9\text{ A}$, $R_G = 9.1\text{ }\Omega$, $R_D = 8.7\text{ }\Omega$, see fig. 10 ^b | - | 11 | - | ns |
| Rise Time | t_r | | - | 24 | - | |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 53 | - | |
| Fall Time | t_f | | - | 49 | - | |
| Internal Drain Inductance | L_D | Between lead, 6 mm (0.25") from package and center of die contact | - | 4.5 | - | nH |
| Internal Source Inductance | L_S | | - | 7.5 | - | |



| SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | | | |
|---|----------|---|------|------|------|---------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| Drain-Source Body Diode Characteristics | | | | | | |
| Continuous Source-Drain Diode Current | I_S | MOSFET symbol showing the integral reverse p - n junction diode  | - | - | 14 | A |
| Pulsed Diode Forward Current ^a | I_{SM} | | - | - | 56 | |
| Body Diode Voltage | V_{SD} | $T_J = 25\text{ }^\circ\text{C}$, $I_S = 14\text{ A}$, $V_{GS} = 0\text{ V}^b$ | - | - | 1.8 | V |
| Body Diode Reverse Recovery Time | t_{rr} | $T_J = 25\text{ }^\circ\text{C}$, $I_F = 7.9\text{ A}$, $dI/dt = 100\text{ A}/\mu\text{s}^b$ | - | 250 | 500 | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | | - | 2.3 | 4.6 | μC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D) | | | | |

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS $25\text{ }^\circ\text{C}$, unless otherwise noted

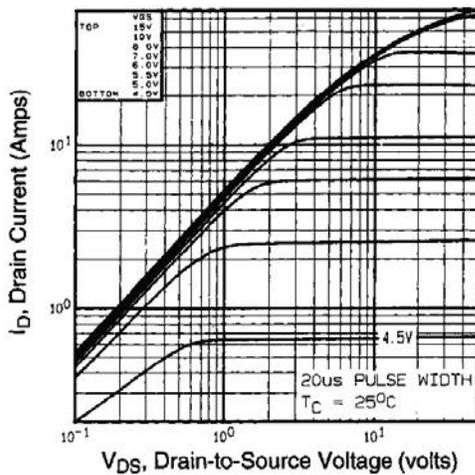


Fig. 1 - Typical Output Characteristics, $T_C = 25\text{ }^\circ\text{C}$

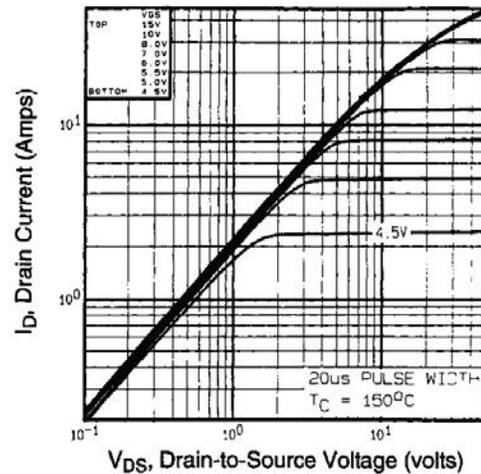


Fig. 2 - Typical Output Characteristics, $T_C = 150\text{ }^\circ\text{C}$

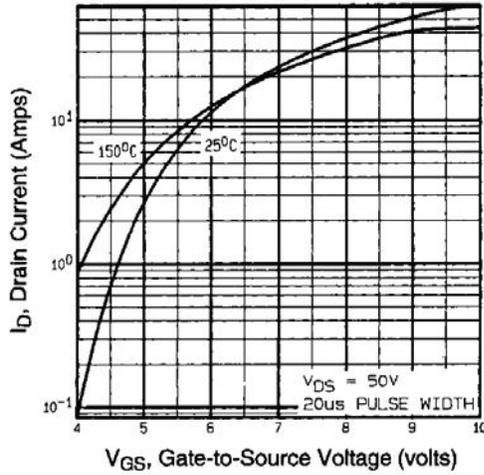


Fig. 3 - Typical Transfer Characteristics

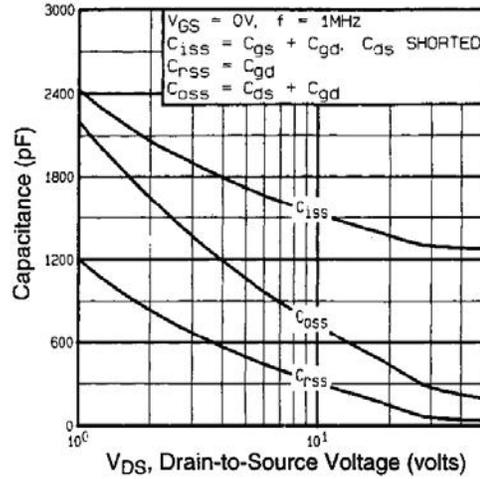


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

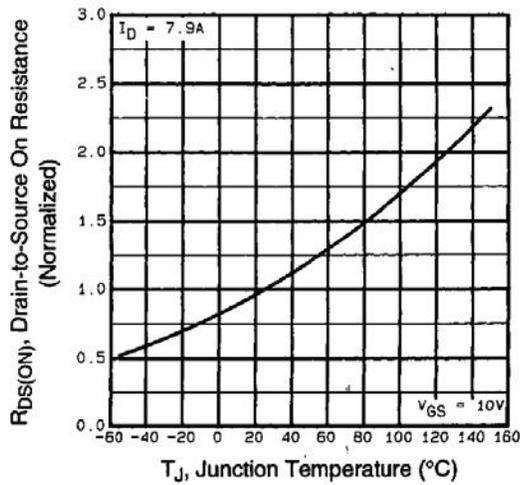


Fig. 4 - Normalized On-Resistance vs. Temperature

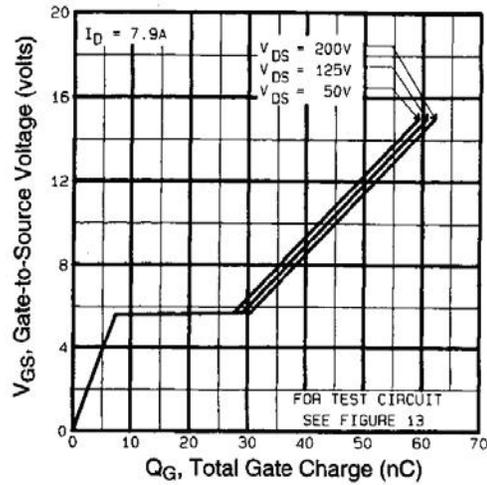


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

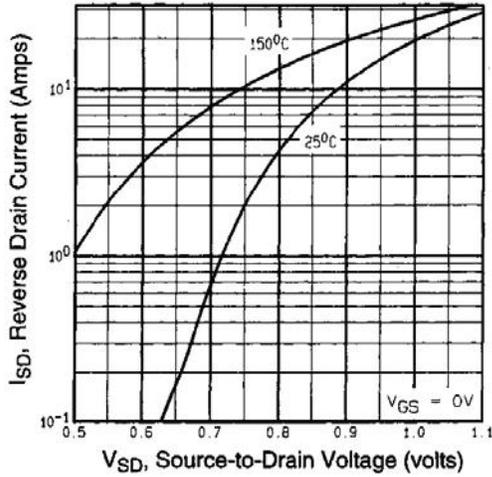


Fig. 7 - Typical Source-Drain Diode Forward Voltage

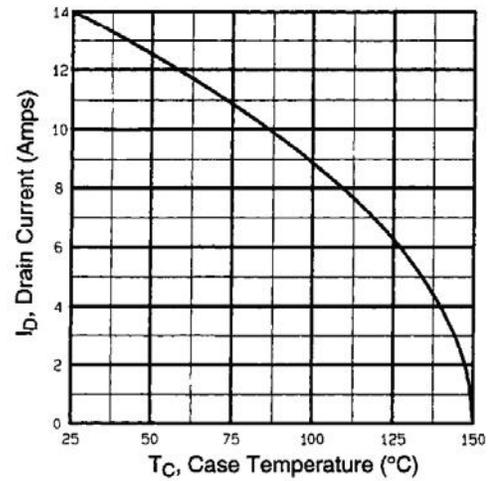


Fig. 9 - Maximum Drain Current vs. Case Temperature

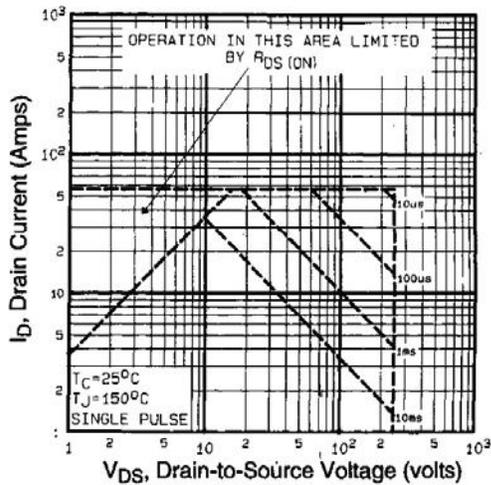


Fig. 8 - Maximum Safe Operating Area

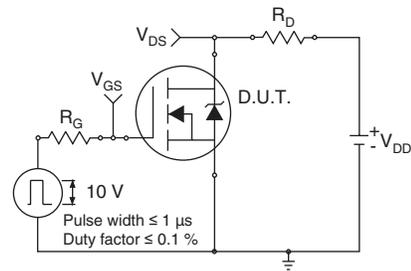


Fig. 10a - Switching Time Test Circuit

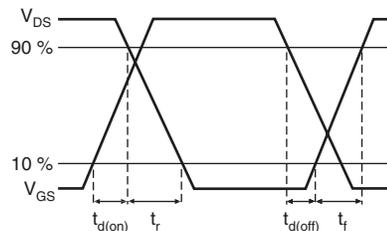


Fig. 10b - Switching Time Waveforms

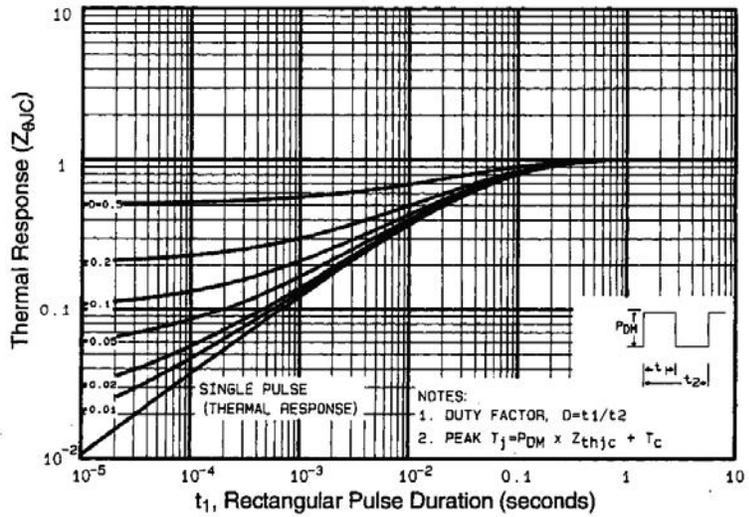


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

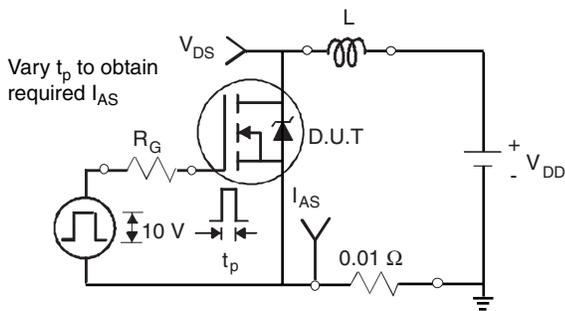


Fig. 12a - Unclamped Inductive Test Circuit

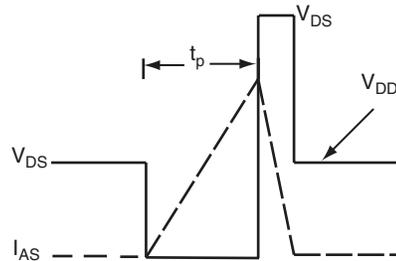


Fig. 12b - Unclamped Inductive Waveforms

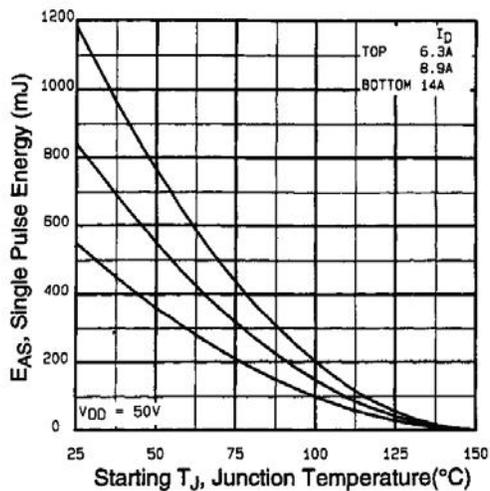


Fig. 13 - Maximum Avalanche Energy vs. Drain Current

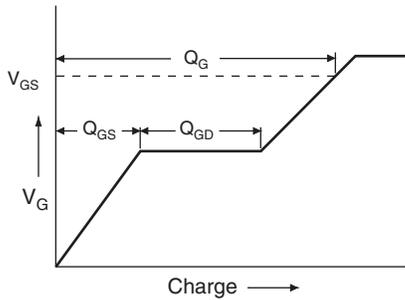


Fig. 13a - Basic Gate Charge Waveform

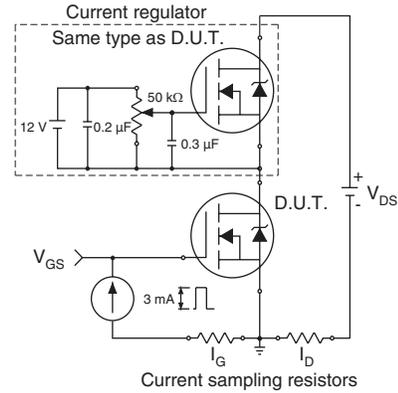
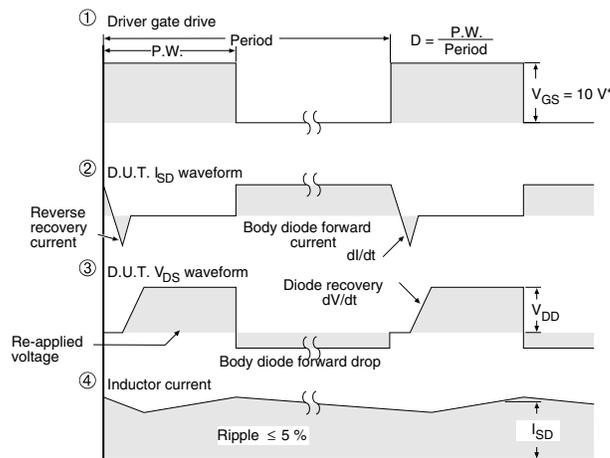
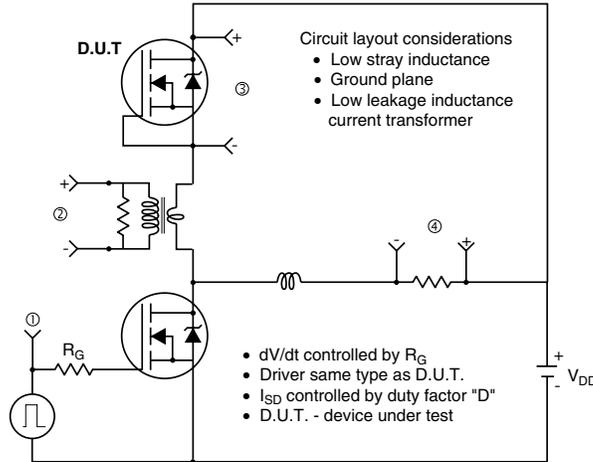


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5V$ for logic level devices

Fig. 14 - For N-Channel

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